

# Synchronization Scheme for a High Frequency Hysteretic Controlled DC-DC Buck converter

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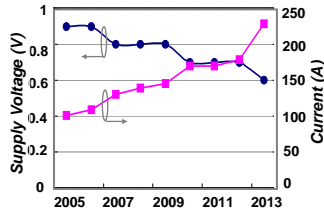
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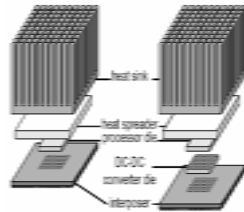
## High-Frequency Near-Load DC-DC converters

In order to cope with the fast current demands and stringent voltage tolerance requirements in performance products, near-load power delivery solutions based on high-frequency low voltage dc-dc converters have been proposed. Integrating the voltage regulator module near or within the processing die for localized power delivery has several advantages.

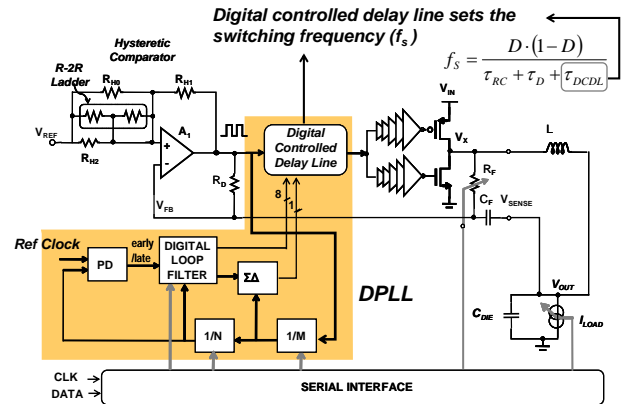
- High voltage conversion ratios near the load trades voltage for current efficiency to reduce external peak currents and relax stringent impedance requirements of packages and board level traces.
- High frequency converters lead to a reduction in capacitor and inductor sizes by several orders of magnitude.
- Faster load response to cope with fast localized transients.
- Localized and efficient power delivery systems naturally lend themselves to multiple voltage domains for multi-core processing architectures.



Processor's voltage and current  
(Source: ITRS Roadmap, 2006)



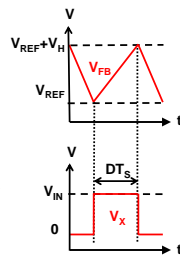
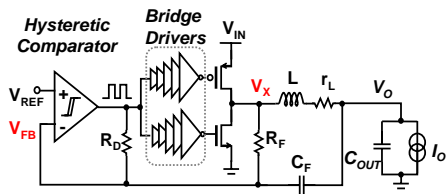
## Digital PLL Synchronized Converter



## Frequency Locked Converter

## Hysteretic Controlled Buck Converter

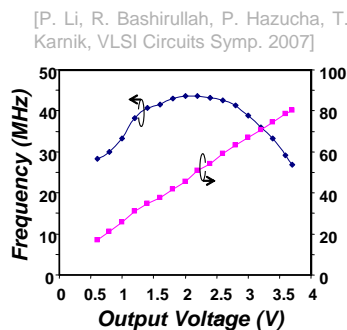
Hysteretic control techniques for dc-dc switched buck converters based on a simple feedback loop achieves a near immediate load response without stability issues.



The switching frequency of the hysteretic controlled buck converter exhibits a strong dependence on voltage conversion ratio:

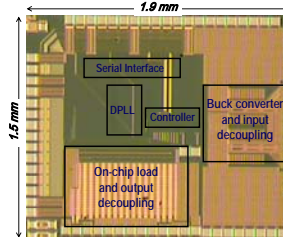
$$f_s = \frac{D \cdot (1-D)}{\tau_{RC} + \tau_D}$$

If kept unchecked, the free-running oscillations may fall in undesired power supply resonance bands created by parasitic package inductance interconnects and on-die decoupling capacitances.

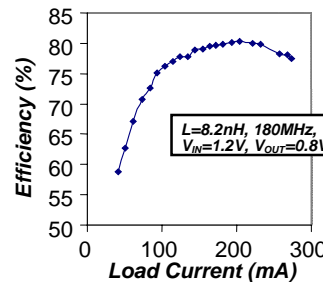


This can potentially generate large voltage excursions in the supply network due to high impedance peaks formed by the multi-resonant networks, compromising overall system operation and device reliability. Therefore, ideally it is desirable to synchronize the converter to an on-chip clock generated from within the processor to mitigate noise injection in undesirable frequency bands.

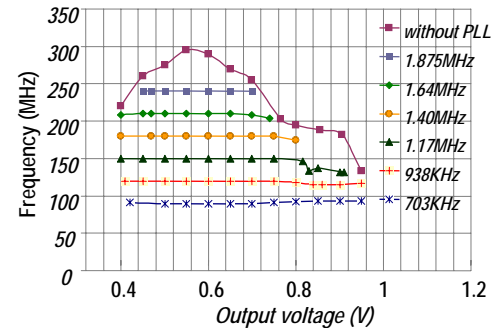
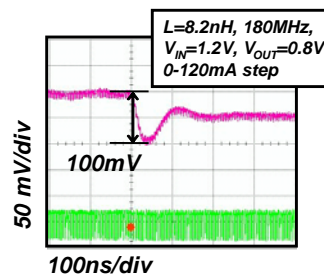
## 130nm 1P-8M Digital CMOS



## Efficiency



## Load Response



## Performance Summary

Technology	130nm CMOS 8M1P
Chip area	2.85mm <sup>2</sup>
DC-DC converter area	0.42mm <sup>2</sup>
Bridge area, A <sub>BRDG</sub>	0.03mm <sup>2</sup>
Decoupling Capacitance	20nF
Inductance, L	8.2nH
Input voltage, V <sub>IN</sub>	1.2V
Output voltage, V <sub>OUT</sub>	0.4V-0.96V
Switching frequency, f	90M-240M
Maximum current, I <sub>MAX</sub>	0.28A
Current density, I <sub>MAX</sub> /A <sub>BRDG</sub>	9.33A/mm <sup>2</sup>
V <sub>IN</sub> =1.2V, V <sub>OUT</sub> =0.8V, f=180MHz	
Droop V <sub>OUT,P-P</sub> @ 0.12A load step	100mV
Efficiency (peak)	80%
Efficiency @ I <sub>MAX</sub>	77.5%

## Acknowledgment

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